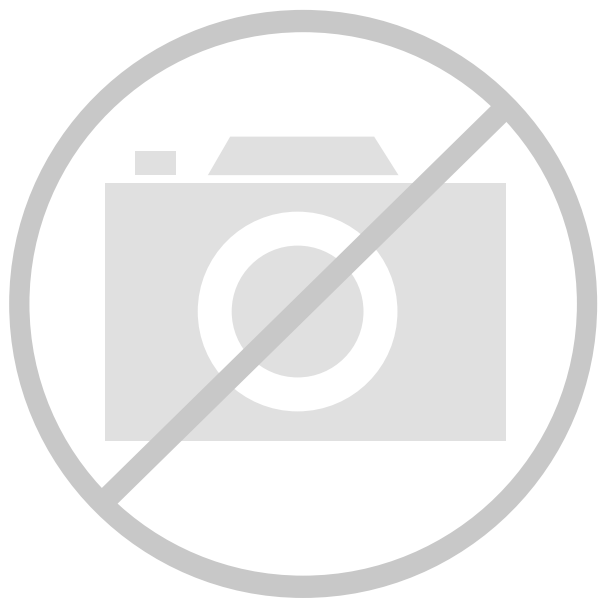




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Details

Product Status	Active
Core Processor	e200z4
Core Size	32-Bit Dual-Core
Speed	150MHz
Connectivity	CANbus, Ethernet, FlexRay, LINbus, SPI, UART/USART
Peripherals	DMA, LVD, POR, WDT
Number of I/O	79
Program Memory Size	2.5MB (2.5M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	384K x 8
Voltage - Supply (Vcc/Vdd)	3.15V ~ 5.5V
Data Converters	A/D 64x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=spc5744pk1amlq5

2.2 Pin/ball descriptions

The following sections provide signal descriptions and related information about the functionality and configuration of the device. Note that this section is under development.

2.2.1 Pin/ball startup and reset states

The following table provides startup state and reset state information for device pins/balls.

The startup state and subsequent states of the following pins/balls cannot be configured by the user:

- JCOMP
- TMS
- TCK
- XTAL/EXTAL
- FCCU_F[0] and FCCU_F[1]
- EXT_POR_B
- RESET_B

The user can configure the state after reset of the following pins/balls by programming the applicable MSCRs/IMCRs:

- GPIOs
- Analog inputs
- TDI
- TDO
- NMI_B
- FAB
- ABS[0]
- ABS[2]

Table 3. Pin/ball startup and reset states

Pin/ball	Startup state ^{1, 2}	State during reset	State after reset	144LQFP	257MAPBGA
GPIOs	hi-z	hi-z	hi-z	Note ³	Note ³
Analog inputs ⁴	hi-z	hi-z	hi-z	Note ³	Note ³
JCOMP (TRST)	hi-z	input, weak pull-down	input, weak pull-down	Note ⁵	Note ⁵
TDI	hi-z	input, weak pull-up	input, weak pull-up	Note ⁵	Note ⁵
TDO	hi-z	output, hi-z	output, hi-z	Note ⁵	Note ⁵
TMS ⁶	hi-z	input, weak pull-up	input, weak pull-up	Note ⁵	Note ⁵

Table continues on the next page...

Table 8. Pin muxing (continued)

Port Pin	SIUL2 MSCR/ IMCR Number	MSCR/ IMCR SSS Value ¹	Signal	Module	Short Signal Description	Dir	LQFP144	BGA257
		0011-1111	—	Reserved	—	—		
	IMCR[48]	0001	SCK	DSPI2	DSPI 2 Input Serial Clock	I		
	IMCR[59]	0010	ETC0	eTimer_0	eTimer_0 Input Data Channel 0	I		
	IMCR[173]	0001	REQ0	SIUL2	SIUL2 External Interrupt 0	I		
A[1]	MSCR[1]	0000 (Default)	GPIO[1]	SIUL2-GPIO[1]	General Purpose IO A[1]	I/O	74	T14
		0001	ETC1	eTimer_0	eTimer_0 Input/Output Data Channel 1	I/O		
		0010	SOUT	DSPI2	DSPI 2 Serial Data Out	O		
		0011-1111	—	Reserved	—	—		
	IMCR[60]	0010	ETC1	eTimer_0	eTimer_0 Input Data Channel 1	I		
	IMCR[174]	0001	REQ1	SIUL2	SIUL2 External Interrupt Source 1	I		
A[2]	MSCR[2]	0000 (Default)	GPIO[2]	SIUL2-GPIO[2]	General Purpose IO A[2]	I/O	84	L14
		0001	ETC2	eTimer_0	eTimer_0 Input/Output Data Channel 2	I/O		
		0010	—	Reserved	—	—		
		0011	A3	FlexPWM_0	FlexPWM_0 Channel A Input/Output 3	I/O		
		0100-1111	—	Reserved	—	—		
	IMCR[169]	0000 (Default)	ABS0	MC_RGM	RGM external boot mode 1	I		
	IMCR[47]	0010	SIN	DSPI2	DSPI 2 Serial Data Input	I		
	IMCR[61]	0010	ETC2	eTimer_0	eTimer_0 Input Data Channel 2	I		
	IMCR[97]	0001	A3	FlexPWM_0	FlexPWM_0 Channel A Input 3	I		
	IMCR[175]	0001	REQ2	SIUL2	SIUL2 External Interrupt Source 2	I		
A[3]	MSCR[3]	0000 (Default)	GPIO[3]	SIUL2-GPIO[3]	General Purpose IO A[3]	I/O	92	G15
		0001	ETC3	eTimer_0	eTimer_0 Input/Output Data Channel 3	I/O		
		0010	CS0	DSPI2	DSPI 2 Peripheral Chip Select 0	I/O		
		0011	B3	FlexPWM_0	FlexPWM_0 Channel B Input/Output 3	I/O		
		0100-1111	—	Reserved	—	—		
	IMCR[171]	0000 (Default)	ABS2	MC_RGM	RGM external boot mode 2	I		
	IMCR[62]	0010	ETC3	eTimer_0	eTimer_0 Input Data Channel 3	I		

Table continues on the next page...

Table 8. Pin muxing (continued)

Port Pin	SIUL2 MSCR/ IMCR Number	MSCR/ IMCR SSS Value ¹	Signal	Module	Short Signal Description	Dir	LQFP144	BGA257
		0011	X2	FlexPWM_0	FlexPWM_0 Auxiliary Input/ Output 2	I/O		
		0100-1111	—	Reserved	—	—		
	IMCR[49]	0010	CS0	DSPI2	DSPI 2 Peripheral Chip Select 0	I/O		
	IMCR[89]	0001	B0	FlexPWM_0	FlexPWM_0 Channel B Input 0	I		
	IMCR[96]	0001	X2	FlexPWM_0	FlexPWM_0 Auxiliary Input 2	I		
	IMCR[182]	0001	REQ9	SIUL2	SIUL2 External Interrupt Source 9	I		
	IMCR[214]	0011	SENT_RX[1]	SENT_1	SENT 1 Receiver channel 1	I		
A[11]	MSCR[11]	0000 (Default)	GPIO[11]	SIUL2-GPIO[11]	General Purpose IO A[11]	I/O	120	D10
		0001	SCK	DSPI2	DSPI 2 Input/Output Serial Clock	I/O		
		0010	A0	FlexPWM_0	FlexPWM_0 Channel A Input/ Output 0	I/O		
		0011	A2	FlexPWM_0	FlexPWM_0 Channel A Input/ Output 2	I/O		
		0100-1111	—	Reserved	—	—		
	IMCR[48]	0010	SCK	DSPI2	DSPI 2 Input Serial Clock	I		
	IMCR[88]	0001	A0	FlexPWM_0	FlexPWM_0 Channel A Input 0	I		
	IMCR[94]	0001	A2	FlexPWM_0	FlexPWM_0 Channel A Input 2	I		
	IMCR[183]	0001	REQ10	SIUL2	SIUL2 External Interrupt Source 10	I		
A[12]	MSCR[12]	0000 (Default)	GPIO[12]	SIUL2-GPIO[12]	General Purpose IO A[12]	I/O	122	D7
		0001	SOUT	DSPI2	DSPI 2 Serial Data Out	O		
		0010	A2	FlexPWM_0	FlexPWM_0 Channel A Input/ Output 2	I/O		
		0011	B2	FlexPWM_0	FlexPWM_0 Channel B Input/ Output 2	I/O		
		0100-1111	—	Reserved	—	—		
	IMCR[94]	0010	A2	FlexPWM_0	FlexPWM_0 Channel A Input 2	I		
	IMCR[95]	0001	B2	FlexPWM_0	FlexPWM_0 Channel B Input 2	I		
	IMCR[184]	0001	REQ11	SIUL2	SIUL2 External Interrupt Source 11	I		
A[13]	MSCR[13]	0000 (Default)	GPIO[13]	SIUL2-GPIO[13]	General Purpose IO A[13]	I/O	136	C5
		0001	—	Reserved	—	—		
		0010	B2	FlexPWM_0	FlexPWM_0 Channel B Input/ Output 2	I/O		

Table continues on the next page...

Table 8. Pin muxing (continued)

Port Pin	SIUL2 MSCR/ IMCR Number	MSCR/ IMCR SSS Value ¹	Signal	Module	Short Signal Description	Dir	LQFP144	BGA257
	IMCR[191]	0001	REQ18	SIUL2	SIUL2 External Interrupt Source 18	I		
B[7]	MSCR[23]	0000 (Default)	GPI[23] ⁴ ADC0_AN[0]	SIUL2-GPI[23]	General Purpose Input B[7]	I	43	R5
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
	IMCR[165]	0010	RXD	LIN0	LIN 0 Receive Pin	I		
B[8]	MSCR[24]	0	GPI[24] ⁴ ADC0_AN[1]	SIUL2-GPI[24]	General Purpose Input B[8]	I	47	P7
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
	IMCR[64]	0001	ETC5	eTimer_0	eTimer_0 Input Data Channel 5	I		
B[9]	MSCR[25]	0000 (Default)	GPI[25] ⁴ ADC0_ADC1_AN[11]	SIUL2-GPI[25]	General Purpose Input B[9]	I	52	U7
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
B[10]	MSCR[26]	0000 (Default)	GPI[26] ⁴ ADC0_ADC1_AN[12]	SIUL2-GPI[26]	General Purpose Input B[10]	I	53	R8
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
B[11]	MSCR[27]	0000 (Default)	GPI[27] ⁴ ADC0_ADC1_AN[13]	SIUL2-GPI[27]	General Purpose Input B[11]	I	54	T8
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
B[12]	MSCR[28]	0000 (Default)	GPI[28] ⁴ ADC0_ADC1_AN[14]	SIUL2-GPI[28]	General Purpose Input B[12]	I	55	U8
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
B[13]	MSCR[29]	0000 (Default)	GPI[29] ⁴ ADC1_AN[0]	SIUL2-GPI[29]	General Purpose Input B[13]	I	60	R10
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		
	IMCR[166]	0001	RXD	LIN1	LIN 1 Receive Pin	I		
B[14]	MSCR[30]	0000 (Default)	GPI[30] ⁴ ADC1_AN[1]	SIUL2-GPI[30]	General Purpose Input B[14]	I	64	P11
		0001	—	Reserved	—	—		
		0010-1111	—	Reserved	—	—		

Table continues on the next page...

Table 8. Pin muxing (continued)

Port Pin	SIUL2 MSCR/ IMCR Number	MSCR/ IMCR SSS Value ¹	Signal	Module	Short Signal Description	Dir	LQFP144	BGA257
		0010	ETC1	eTimer_2	eTimer_2 Input/Output Data Channel 1	I/O		
		0011	MDIO	ENET_0	Ethernet MDIO input/output data	I/O		
		0100-1111	—	Reserved	—	—		
	IMCR[72]	0001	ETC1	eTimer_2	eTimer_2 Input Data Channel 1	I		
H[8]	MSCR[120]	0000 (Default)	GPIO[120]	SIUL2-GPIO[120]	General Purpose IO H[8]	I/O		L1
		0001	A1	FlexPWM_1	FlexPWM_1 Channel A Input/Output 1	I/O		
		0010	—	Reserved	—	—		
		0011	CS6	DSPI0	DSPI 0 Peripheral Chip Select 6	O		
		0100-1111	—	Reserved	—	—		
	IMCR[109]	0010	A1	FlexPWM_1	FlexPWM_1 Channel A Input 1	I		
	IMCR[228]	0001	RX_D2	ENET_0	Ethernet MII Receive Data 2	I		
H[9]	MSCR[121]	0000 (Default)	GPIO[121]	SIUL2-GPIO[121]	General Purpose IO H[9]	I/O		B13
		0001	B1	FlexPWM_1	FlexPWM_1 Channel B Input/Output 1	I/O		
		0010	—	Reserved	—	—		
		0011	CS7	DSPI0	DSPI 0 Peripheral Chip Select 7	O		
		0100-1111	—	Reserved	—	—		
	IMCR[110]	0010	B1	FlexPWM_1	FlexPWM_1 Channel B Input 1	I		
H[10]	MSCR[122]	0000 (Default)	GPIO[122]	SIUL2-GPIO[122]	General Purpose IO H[10]	I/O		C7
		0001	X2	FlexPWM_1	FlexPWM_1 Auxiliary Input/Output 2	I/O		
		0010	ETC2	eTimer_2	eTimer_2 Input/Output Data Channel 2	I/O		
		0011-1111	—	Reserved	—	—		
	IMCR[73]	0010	ETC2	eTimer_2	eTimer_2 Input Data Channel 2	I		
H[11]	MSCR[123]	0000 (Default)	GPIO[123]	SIUL2-GPIO[123]	General Purpose IO H[11]	I/O		C9
		0001	A2	FlexPWM_1	FlexPWM_1 Channel A Input/Output 2	I/O		
		0010-1111	—	Reserved	—	—		
	IMCR[112]	0010	A2	FlexPWM_1	FlexPWM_1 Channel A Input 2	I		
H[12]	MSCR[124]	0000 (Default)	GPIO[124]	SIUL2-GPIO[124]	General Purpose IO H[12]	I/O		A7

Table continues on the next page...

Table 10. Peripheral muxing (continued)

Destination peripheral	Destination functions	IMCR number	IMCR[SSS] field value	Source peripherals	Source functions
			0100-1111	—	Reserved
FlexPWM_0	X2	IMCR[96]	0000 (Default)	—	Disable
			0001	I/O-Pad	A[10]
			0010	I/O-Pad	G[2]
			0011-1111	—	Reserved
FlexPWM_0	A3	IMCR[97]	0000 (Default)	—	Disable
			0001	I/O-Pad	A[2]
			0010	I/O-Pad	C[10]
			0011	I/O-Pad	D[3]
			0100	I/O-Pad	G[6]
			0101-1111	—	Reserved
FlexPWM_0	B3	IMCR[98]	0000 (Default)	—	Disable
			0001	I/O-Pad	A[3]
			0010	I/O-Pad	A[9]
			0011	I/O-Pad	D[4]
			0100	I/O-Pad	G[7]
			0101-1111	—	Reserved
FlexPWM_0	X3	IMCR[99]	0000 (Default)	—	Disable
			0001	I/O-Pad	D[2]
			0010	I/O-Pad	D[6]
			0011	I/O-Pad	G[5]
			0100-1111	—	Reserved
FlexPWM_1	FAULT0	IMCR[100]	0000 (Default)	—	Disable
			0001	I/O-Pad	I[0]
			0010-1111	—	Reserved
FlexPWM_1	FAULT1	IMCR[101]	0000 (Default)	—	Disable
			0001	I/O-Pad	I[1]
			0010-1111	—	Reserved
FlexPWM_1	FAULT2	IMCR[102]	0000 (Default)	—	Disable
			0001	I/O-Pad	I[2]
			0010-1111	—	Reserved
FlexPWM_1	FAULT3	IMCR[103]	0000 (Default)	—	Disable
			0001	I/O-Pad	I[3]
			0010-1111	—	Reserved
FlexPWM_1	A0	IMCR[105]	0000 (Default)	—	Disable
			0001	I/O-Pad	C[13]
			0010	I/O-Pad	H[5]
			0011-1111	—	Reserved
FlexPWM_1	B0	IMCR[106]	0000 (Default)	—	Disable

Table continues on the next page...

Table 10. Peripheral muxing (continued)

Destination peripheral	Destination functions	IMCR number	IMCR[SSS] field value	Source peripherals	Source functions
			0001	I/O-Pad	C[14]
			0010	I/O-Pad	H[6]
			0011-1111	—	Reserved
FlexPWM_1	A1	IMCR[109]	0000 (Default)	—	Disable
			0001	I/O-Pad	F[12]
			0010	I/O-Pad	H[8]
			0011-1111	—	Reserved
FlexPWM_1	B1	IMCR[110]	0000 (Default)	—	Disable
			0001	I/O-Pad	F[13]
			0010	I/O-Pad	H[9]
			0011-1111	—	Reserved
FlexPWM_1	A2	IMCR[112]	0000 (Default)	—	Disable
			0001	I/O-Pad	A[4]
			0010	I/O-Pad	H[11]
			0011-1111	—	Reserved
FlexPWM_1	B2	IMCR[113]	0000	—	Disable
			0001	I/O-Pad	E[14]
			0010	I/O-Pad	H[12]
			0011-1111	—	Reserved
FlexRay	FR_A_RX	IMCR[136]	0000 (Default)	—	Disable
			0001	I/O-Pad	D[1]
			0010-1111	—	Reserved
FlexRay	FR_B_RX	IMCR[137]	0000 (Default)	—	Disable
			0001	I/O-Pad	D[2]
			0010-1111	—	Reserved
LIN_0	RXD	IMCR[165]	0000 (Default)	—	Disable
			0001	I/O-Pad	B[3]
			0010	I/O-Pad	B[7]
			0011-1111	—	Reserved
LIN_1	RXD	IMCR[166]	0000 (Default)	—	Disable
			0001	I/O-Pad	B[13]
			0010	I/O-Pad	D[12]
			0011	I/O-Pad	F[15]
			0100-1111	—	Reserved
MC_RGM	ABS0	IMCR[169]	0000 (Default)	I/O-Pad	A[2]
			0001	—	Disable
			0010-1111	—	Reserved
MC_RGM	ABS2	IMCR[171]	0000 (Default)	I/O-Pad	A[3]
			0001	—	Disable

Table continues on the next page...

Table 11. Peripheral muxing example

SSS field value in IMCR[214]	Result
0001	I/O-Pad I[12] is connected to SENT_1 Receive input SENT_RX[1]
0010	I/O-Pad J[6] is connected to SENT_1 Receive input SENT_RX[1]

See [Table 9](#) concerning the availability of port pins on the packages.

3 Electrical characteristics

3.1 Introduction

This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications for this device.

This device is designed to operate at 200 MHz.

3.2 165°C junction temperature option

For orderable parts whose device marking shows they support this extended temperature option:

- Operation at $150^{\circ}\text{C} < T_J < 165^{\circ}\text{C}$ is allowed for a maximum cumulative time of 200 hours over the device lifetime.
- Production parameters at 165°C reflect testing over an ambient temperature range of -40°C to 150°C with appropriate guardbanding to guarantee operation at 165°C .

3.3 Absolute maximum ratings

NOTE

Functional operating conditions appear in the DC electrical characteristics. Absolute maximum ratings are stress ratings only, and functional operation at the maximum values is not guaranteed.

- Absolute maximum supply: $V_{DD_HV_ADREx} = 6.0\text{ V}$ (10 hours, device in reset—no switching)
- Absolute maximum supply: $V_{DD_HV_ADREx} = 5.5\text{ V}$ (always)
- Absolute maximum ADC input pin voltage = 7.0 V (60 seconds lifetime), when V_{DD_HV} is connected to the 5 V
- Absolute maximum ADC input pin voltage = 6.5 V (always while respecting 5 mA maximum injection), when V_{DD_HV} is connected to the 5 V

3.4 Recommended operating conditions

NOTE

Full functionality cannot be guaranteed when voltage drops below 3.0 V . In particular, ADC electrical characteristics and DC electrical specifications for I/Os might not be guaranteed.

Table 13. Recommended operating conditions ($V_{DD_HV_xx} = 3.3\text{ V}$)

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DD_HV_PMU}^1$	3.3 V voltage regulator supply voltage	—	3.15	3.6	V
$V_{DD_HV_IO}^2$	3.3 V input/output supply voltage	—	3.15	3.6	V
$V_{SS_HV_IO}$	Input/output ground voltage	—	0	0	V
$V_{DD_HV_FLA}^3$	3.3 V flash supply voltage	—	3.15	3.6	V
$V_{SS_HV_FLA}$	Flash memory ground	—	0	0	V
$V_{DD_HV_OSC}^4$	3.3 V crystal oscillator amplifier supply voltage	—	3.15	3.6	V
$V_{SS_HV_OSC}$	3.3 V crystal oscillator amplifier ground	—	0	0	V
$V_{DD_HV_ADRE0}$ $V_{DD_HV_ADRE1}$	3.3 V / 5.0 V ADC_0 high reference voltage 3.3 V / 5.0 V ADC_1 high reference voltage	$T_J \leq 150^\circ\text{C}$	3.15 to 5.5		V
$V_{DD_HV_ADRE0}^5$ $V_{DD_HV_ADRE1}$	3.3 V / 5.0 V ADC_0 high reference voltage 3.3 V / 5.0 V ADC_1 high reference voltage	$150^\circ\text{C} < T_J < 165^\circ\text{C}$ (only for corresponding marked parts)	3.15 to 5.25		V
$V_{SS_HV_ADRE0}^5$ $V_{SS_HV_ADRE1}$	ADC_0 ground and low reference voltage ADC_1 ground and low reference voltage	—	0	0	V
$V_{DD_HV_ADV}^6$	3.3 V ADC supply voltage	—	3.15	3.6	V
$V_{SS_HV_ADV}$	3.3 V ADC supply ground	—	0	0	V
$V_{DD_LV_COR}^7$	Core supply, $1.25\text{ V} \pm 5\%$	—	1.19	1.32	V
$V_{DD_LV_CORx}$	Internal supply voltage	—	—	—	V
$V_{SS_LV_CORx}$	Internal reference voltage	—	0	0	V
$V_{DD_LV_PLL}$	Internal PLL supply voltage	—	1.19	1.32	V
$V_{SS_LV_PLL}$	Internal PLL reference voltage	—	0	0	V
$V_{DD_LV_NEXUS}$	Aurora LVDS supply voltage	—	1.19	1.32	V
$V_{SS_LV_NEXUS}$	Aurora LVDS supply ground	—	0	0	V
$V_{DD_LV_LFAST}$	LFAST PLL supply voltage	—	1.19	1.32	V
$V_{SS_LV_LFAST}$	LFAST PLL supply ground	—	0	0	V
I_{IC}	DC injection current per pin ^{8, 9, 10}	Digital pins	-3.0	3.0	mA
		Analog pins	-3.0	3.0	

Table continues on the next page...

To determine the junction temperature of the device in the application when heat sinks are not used, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using this equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

- T_T = thermocouple temperature on top of the package ($^{\circ}\text{C}$)
- Ψ_{JT} = thermal characterization parameter ($^{\circ}\text{C}/\text{W}$)
- P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

3.5.1.1 References

Semiconductor Equipment and Materials International; 3081 Zanker Road; San Jose, CA 95134 USA; (408) 943-6900

MIL-SPEC and EIA/JESD (JEDEC) specifications are available from Global Engineering Documents at 800-854-7179 or 303-397-7956.

JEDEC specifications are available on the Web at <http://www.jedec.org>.

1. C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
2. G. Kromann, S. Shidore, and S. Addison, "Thermal Modeling of a PBGA for Air-Cooled Applications," Electronic Packaging and Production, pp. 53–58, March 1998.
3. B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

3.6 Electromagnetic compatibility (EMC)

Tests were carried out in accordance with the International Electrotechnical Commission specifications:

- IEC 61967: Integrated Circuits, Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz
- IEC 61967-2: Measurement of radiated emissions – TEM-cell and wideband TEM-cell method

Parameter	Test #	Conditions ¹		Classification level ²	Unit
		Comm. modules ³	GPIO		
V _{EME}	1	On	Off, input pull-up	L	dBμV
	2	On	Off, input pull-up	L	dBμV
	3	On	Off, input pull-up	L	dBμV
	4	On	Off, input pull-up	— ⁴	dBμV
	5	On	Off, input pull-up	L	dBμV
	6	On	PG1 ⁵ input, pull-up	L	dBμV
	7	Off	PG1 ⁵ output high, half drive	L	dBμV
	8	Off	PG1 ⁵ output high, full drive	L	dBμV
	9	Off	PG1 ⁵ output low, half drive	L	dBμV
	10	Off	PG1 ⁵ output low, full drive	L	dBμV
	11	Off	All I/O tri-stated	I	dBμV
	12	Off	PG2 ⁶ toggle @ 5 kHz, half drive, SR off	L	dBμV
	13	Off	PG2 ⁶ toggle @ 5 kHz, half drive, SR on	L	dBμV
	14	Off	PG2 ⁶ toggle @ 5 kHz, full drive, SR off	L	dBμV
	15	Off	PG2 ⁶ toggle @ 5 kHz, full drive, SR on	I	dBμV

1. All tests ran with core and bus frequency at 200 MHz. Test #2 had "weak" FM modulation and Test #3 had "strong" FM modulation.
2. I = Class 1 (36 dBμV), L = Class 2 (24 dBμV), N = Class 3 (12 dBμV)
3. LINFlex0/1 running at 19.2 kbd, SPI0 running at 2.5 MHz, SPI1 running at 7.5 MHz, SPI2 running at 4.5 MHz, CAN0/1 running at 500 kbd
4. Test #4 values were slightly above class I level.
5. PG1 = port group 1: pins F[3:15]
6. PG2 = port group 2: pins A[2:4], C[11:14], D14, F12, G6, J8

Each of the tests ran once across each of the following frequency bands.

Frequency band	RBW (kHz)	VBW (kHz)	Sweep time (ms/MHz)	Pre-amplifier	Detector
150 kHz to 30 MHz	9	30	5	ON (–20 dB)	Peak-Average
30 MHz to 1000 MHz	120	300			

Table 21. Current consumption characteristics (continued)

Symbol	Parameter	Conditions ¹	Min	Typ	Max	Unit
I _{DD_HV_FLA}	Operating current	Frequency: 200MHz				mA
		T _J = 165 °C	—	—	1.8	
		3.3 V supplies				
		Frequency: 200MHz				
I _{DD_HV_FLA}	Operating current	T _J = 150 °C	—	—	5.5	mA
		3.3 V supplies				
		Frequency: 200MHz				
		T _J = 165 °C	—	—	7.0	
		3.3 V supplies				
		Frequency: 200MHz				

1. The content of the Conditions column identifies the components that draw the specific current.
2. Enabled modules: ADC0/1, FlexPWM0, eTimer0, two SPIs, two FlexCANs, FlexRay, one LINFlexD, DMA. At maximum frequency. I/O supply current excluded.
3. Internal structures hold the input voltage less than V_{DD_HV_ADV} + 1.0 V on all pads powered by V_{DDA} supplies, if the maximum injection current specification is met (3 mA for all pins) and V_{DDA} is within the operating voltage specifications.
4. This value is the total current for two ADCs.

3.11 Temperature sensor

The following table describes the temperature sensor electrical characteristics.

Table 22. Temperature sensor electrical characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
—	Temperature monitoring range	—	−40	—	165	°C
T _{SENS}	Sensitivity	—	—	5.18	—	mV/°C
T _{ACC}	Accuracy for linear temperature sensor	T _J = −40 to 150 °C	−3	—	+3	°C
		T _J = 150 to 165 °C	−5	—	+5	
—	Accuracy for temperature-threshold digital flags	T _J = −40 to 150 °C	−5	—	+5	°C
—	Temperature variation for each customer-adjustable trim step	T _J = −40 to 150 °C	0.4	0.7	1.0	°C
—	Operating current	T _J = −40 to 165 °C	—	—	675	μA

3.12 Main oscillator electrical characteristics

This device provides a driver for the oscillator in pierce configuration with amplitude control. Controlling the amplitude allows a more sinusoidal oscillation, reducing EMI and power consumption. This Loop Controlled Pierce (LCP mode) requires good practices to reduce the stray capacitance of traces between the crystal and the MCU.

3.16 Flash memory specifications

3.16.1 Maximum junction temperature 150°C

3.16.1.1 Flash memory program and erase specifications

NOTE

All timing, voltage, and current numbers specified in this section are defined for a single embedded flash memory within an SoC, and represent average currents for given supplies and operations.

Table 28 shows the estimated Program/Erase times.

Table 28. Flash memory program and erase specifications

Symbol	Characteristic ¹	Typ ²	Factory Programming ^{3, 4}		Field Update			Unit
			Initial Max	Initial Max, Full Temp	Typical End of Life ⁵	Lifetime Max ⁶		
						20°C ≤T _A ≤30°C	-40°C ≤T _J ≤150°C	
t _{dwpgm}	Doubleword (64 bits) program time	43	100	150	55	500		μs
t _{ppgm}	Page (256 bits) program time	73	200	300	108	500		μs
t _{qppgm}	Quad-page (1024 bits) program time	268	800	1,200	396	2,000		μs
t _{16kers}	16 KB Block erase time	168	290	320	250	1,000		ms
t _{16kpgm}	16 KB Block program time	34	45	50	40	1,000		ms
t _{32kers}	32 KB Block erase time	217	360	390	310	1,200		ms
t _{32kpgm}	32 KB Block program time	69	100	110	90	1,200		ms
t _{64kers}	64 KB Block erase time	315	490	590	420	1,600		ms
t _{64kpgm}	64 KB Block program time	138	180	210	170	1,600		ms
t _{256kers}	256 KB Block erase time	884	1,520	2,030	1,080	4,000	—	ms
t _{256kpgm}	256 KB Block program time	552	720	880	650	4,000	—	ms

1. Program times are actual hardware programming times and do not include software overhead. Block program times assume quad-page programming.
2. Typical program and erase times represent the median performance and assume nominal supply values and operation at 25 °C. Typical program and erase times may be used for throughput calculations.
3. Conditions: ≤ 150 cycles, nominal voltage.
4. Plant Programming times provide guidance for timeout limits used in the factory.
5. Typical End of Life program and erase times represent the median performance and assume nominal supply values. Typical End of Life program and erase values may be used for throughput calculations.
6. Conditions: -40°C ≤ T_J ≤ 150°C, full spec voltage.

Table 33. Flash memory Array Integrity and Margin Read specifications (continued)

Symbol	Characteristic	Min	Typical	Max ¹	Units ²
$t_{ai32kseq}$	Array Integrity time for sequential sequence on 32KB block.	—	—	1024 x T_{period} x N_{read}	—
$t_{ai64kseq}$	Array Integrity time for sequential sequence on 64KB block.	—	—	2048 x T_{period} x N_{read}	—
$t_{ai256kseq}$	Array Integrity time for sequential sequence on 256KB block.	—	—	8192 x T_{period} x N_{read}	—
$t_{mr16kseq}$	Margin Read time for sequential sequence on 16KB block.	73.81	—	110.7	μs
$t_{mr32kseq}$	Margin Read time for sequential sequence on 32KB block.	128.43	—	192.6	μs
$t_{mr64kseq}$	Margin Read time for sequential sequence on 64KB block.	237.65	—	356.5	μs
$t_{mr256kseq}$	Margin Read time for sequential sequence on 256KB block.	893.01	—	1,339.5	μs

1. Array Integrity times need to be calculated and is dependant on system frequency and number of clocks per read. The equation presented require T_{period} (which is the unit accurate period, thus for 200 MHz, T_{period} would equal $5e-9$) and N_{read} (which is the number of clocks required for read, including pipeline contribution. Thus for a read setup that requires 6 clocks to read with no pipeline, N_{read} would equal 6. For a read setup that requires 6 clocks to read, and has the address pipeline set to 2, N_{read} would equal 4 (or $6 - 2$).)
2. The units for Array Integrity are determined by the period of the system clock. If unit accurate period is used in the equation, the results of the equation are also unit accurate.

3.16.2.3 Flash memory module life specifications

Table 34. Flash memory module life specifications

Symbol	Characteristic	Conditions	Min	Typical	Units
Array P/E cycles	Number of program/erase cycles per block for 16 KB, 32 KB and 64 KB blocks. ¹	-	250,000	-	P/E cycles
	Number of program/erase cycles per block for 256 KB blocks. ²	-	1,000	250,000	P/E cycles
Data retention	Minimum data retention.	Blocks with 0 - 1,000 P/E cycles.	50	-	Years
		Blocks with 100,000 P/E cycles.	20	-	Years
		Blocks with 250,000 P/E cycles.	10	-	Years

1. Program and erase supported across standard temperature specs. Up to 10,000 program and erase cycles may be done between 150 °C and 165 °C out of the total specified number of cycles.
2. Program and erase supported across standard temperature specs.

3.16.2.4 Data retention vs program/erase cycles

Graphically, Data Retention versus Program/Erase Cycles can be represented by the following figure. The spec window represents qualified limits. The extrapolated dotted line demonstrates technology capability, however is beyond the qualification limits.

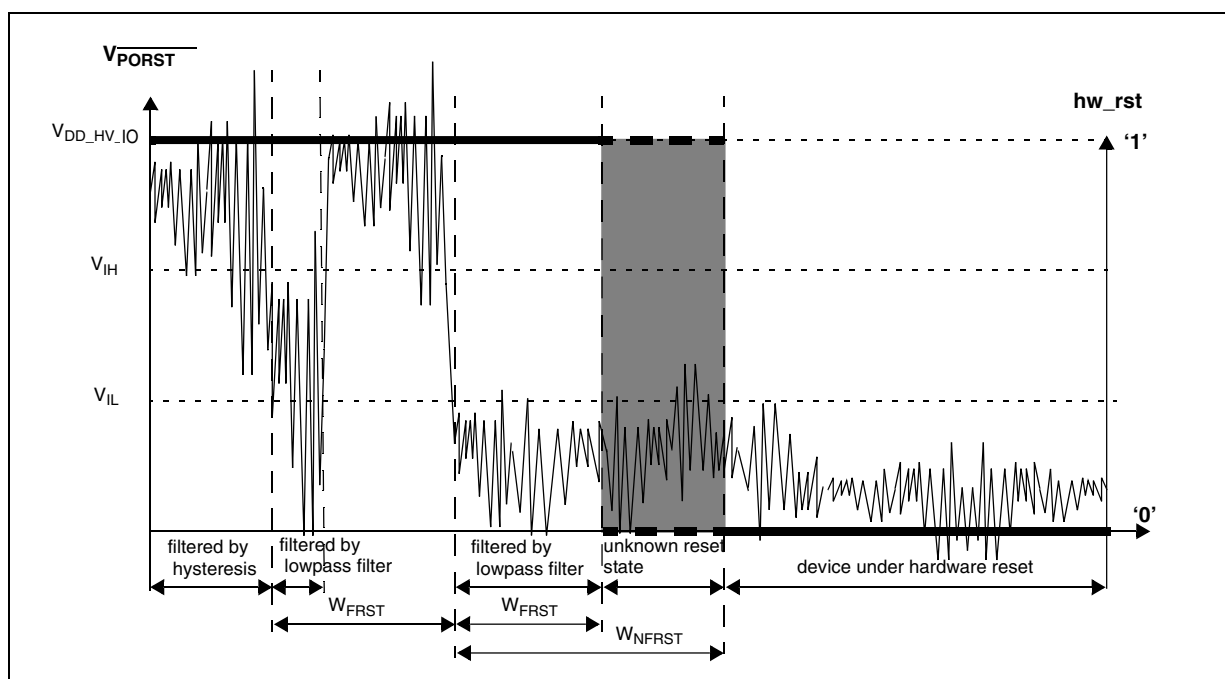


Figure 10. Noise filtering on reset signal

Table 40. Reset ($\overline{\text{RESET}}$) electrical characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
V_{IH}	Input high level TTL (Schmitt Trigger)	—	2.0	—	$V_{DD_HV_IO} + 0.4$	V
V_{IL}	Input low level TTL (Schmitt Trigger)	—	-0.4	—	0.8	V
V_{HYS}	Input hysteresis TTL (Schmitt Trigger)	—	300	—	—	mV
I_{OL_R}	Strong pull-down current	Device under power-on reset $V_{DD_HV_A}=1.0\text{ V}$ $V_{OL} = 0.35 \cdot V_{DD_HV_IO}$	0.2	—	—	mA
		Device under power-on reset $V_{DD_HV_IO}=3.0\text{ V}$ $V_{OL} = 0.35 \cdot V_{DD_HV_IO}$	15	—	—	mA
W_{FRST}	($\overline{\text{RESET}}$)-input filtered pulse	—	—	—	500	ns
W_{NFRST}	($\overline{\text{RESET}}$)-input not filtered pulse	—	2	—	—	μs
$ I_{WPD} $	Weak pull-down current absolute value	RESET pin $V_{IN} = V_{DD}$	30	—	80	μA

1. These specifications apply to JTAG boundary scan only.

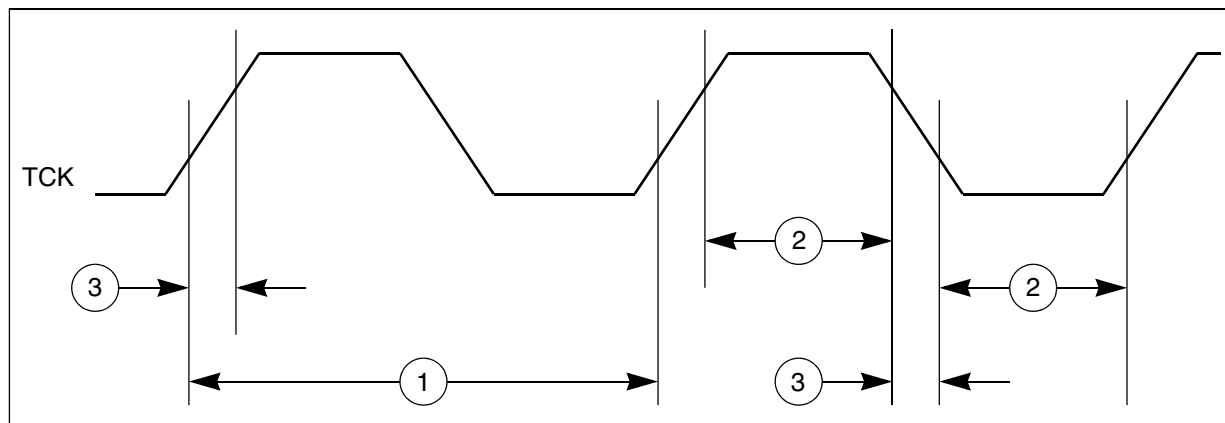


Figure 11. JTAG test clock input timing

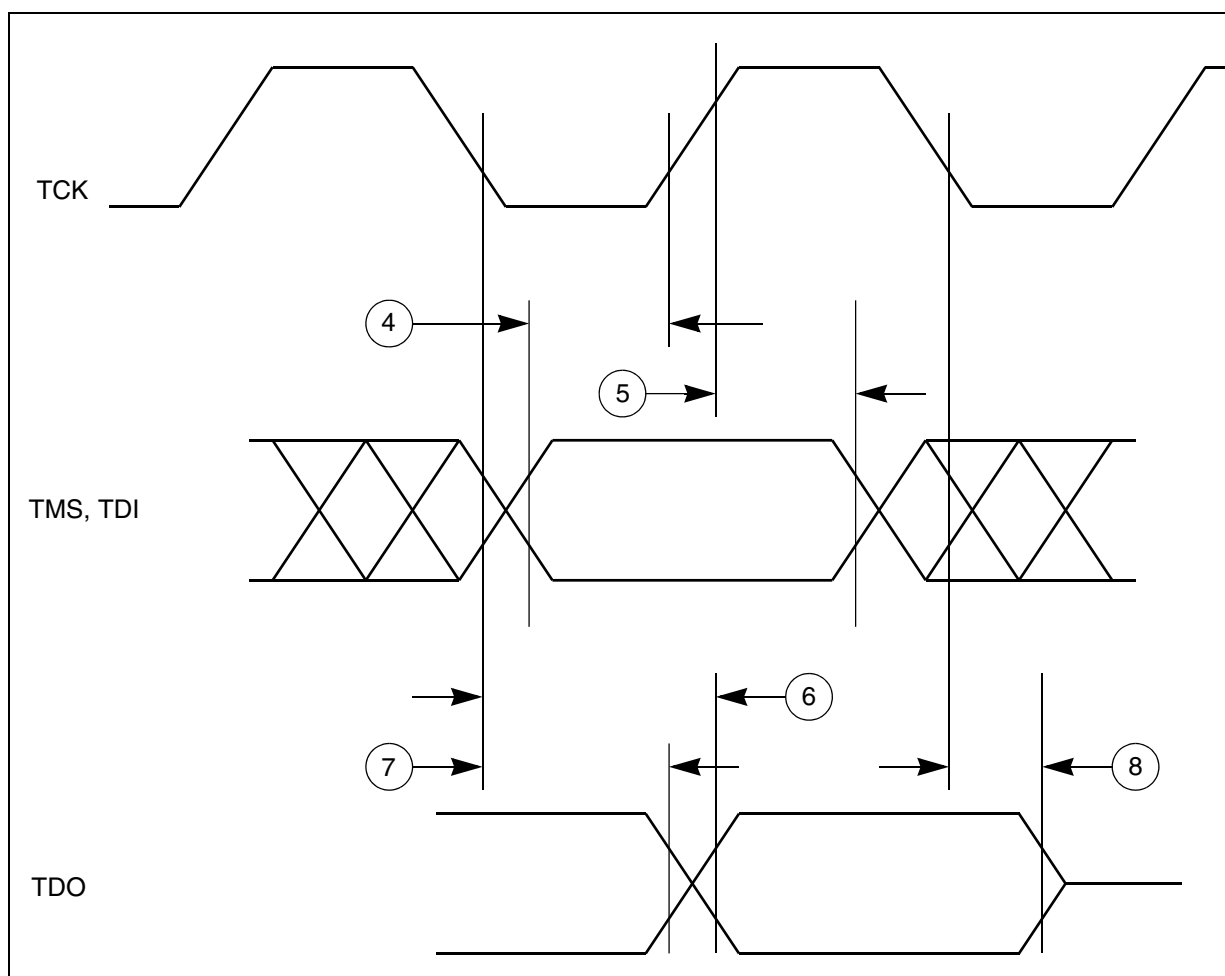


Figure 12. JTAG test access port timing

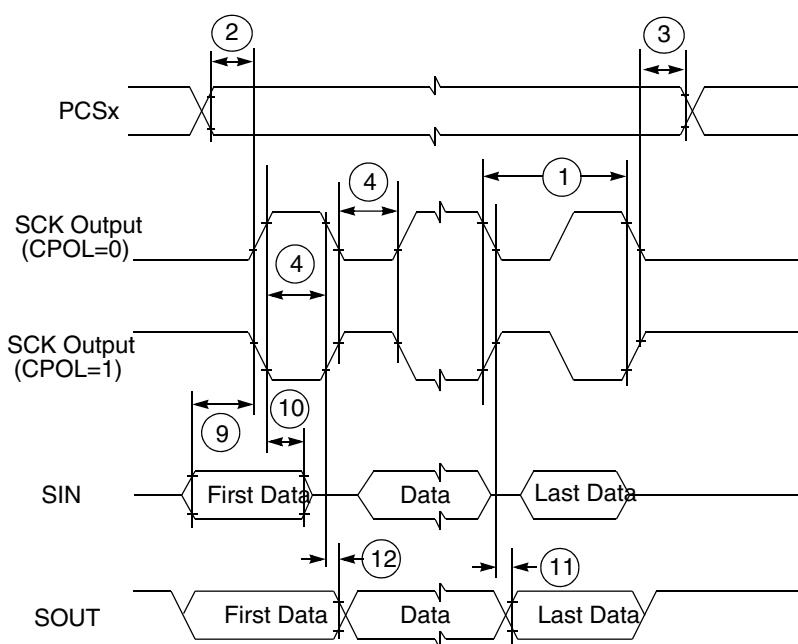
Table 48. SPI timing (continued)

#	Symbol	Parameter	Conditions	Min	Max	Unit
			Master (MTFE = 1, CPHA = 0)	-4	—	
			Master (MTFE = 1, CPHA = 1)	-4	—	

1. Slave Receive Only Mode can operate at a maximum frequency of 60 MHz. In this mode, the SPI can receive data on SIN, but no valid data is transmitted on SOUT.
2. P is the number of clock cycles added to delay the SPI input sample point and is software programmable.
3. t_{SYS} is the period of the DSPI_CLKn clock, the input clock to the SPI module. Maximum frequency is 50 MHz (min t_{SYS} = 20 ns).

NOTE

For numbers shown in the following figures, see [Table 48](#).

**Figure 21. DSPI classic SPI timing — master, CPHA = 0**

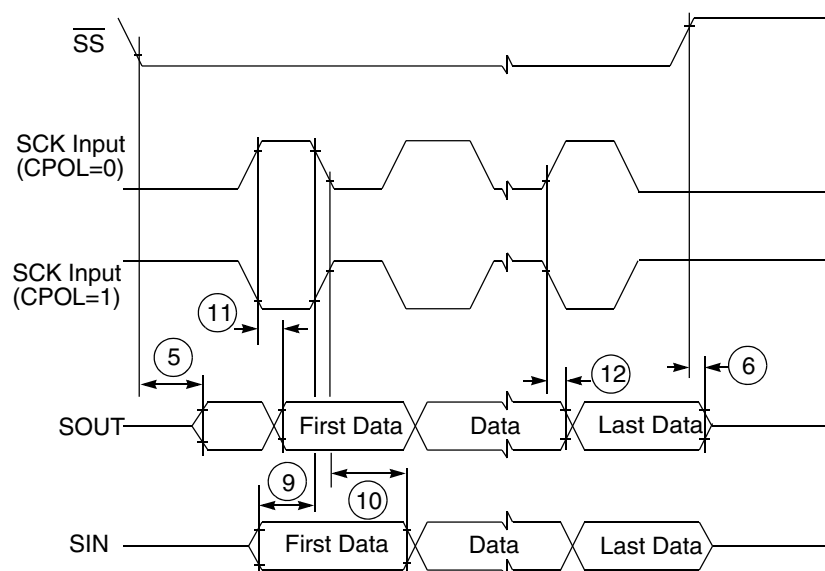


Figure 28. DSPI modified transfer format timing — slave, CPHA = 1

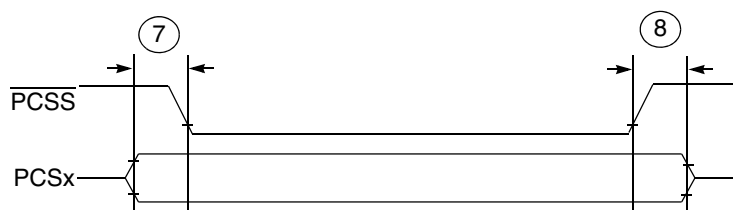


Figure 29. DSPI PCS strobe (PCSS) timing

3.19.6 LFAST

3.19.6.1 LFAST interface timing diagrams

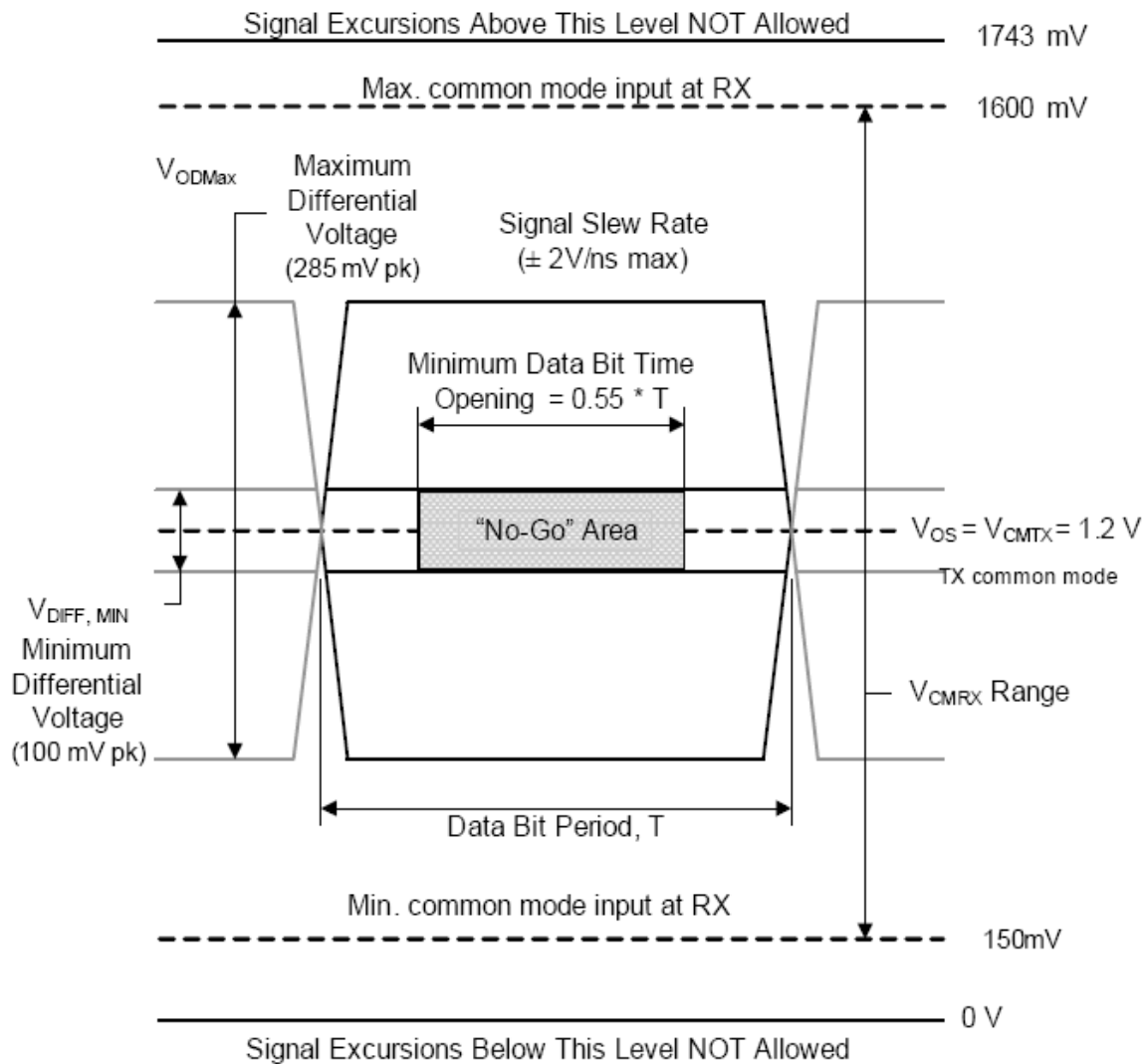
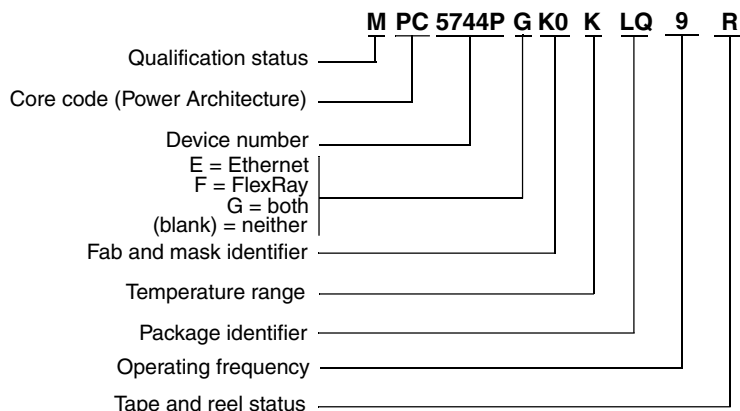


Figure 30. LFAST timing definition

5 Ordering information



Temperature range	Package identifier	Operating frequency	Qualification status	Tape and reel status
M = -40°C to +125°C	LQ = 144 LQFP	9 = 200 MHz	P = Pre-qualification	R = Tape and reel
K = -40°C to +135°C for extended temp (+165°C T _J)	MM = 257 MAPBGA	8 = 180 MHz 5 = 150 MHz	M = Fully spec. qualified, general market flow S = Fully spec. qualified, automotive flow	(blank) = Trays

Note: Not all options are available on all devices.

Table 57. Orderable part number examples

Part number ¹	Flash/SRAM	Package	Other features
SPC5744PFK1MLQ9	2.5 MB/384 KB	144 LQFP (Pb free)	-40 to +125 °C
SPC5744PGK1MMM9	2.5 MB/384 KB	257 MAPBGA (Pb free)	Ethernet interface LFAST interface Nexus Aurora -40 to +125 °C
SPC5743PFK1MLQ9	2 MB/256 KB	144 LQFP (Pb free)	-40 to +125 °C
SPC5743PGK1MMM9	2 MB/256 KB	257 MAPBGA (Pb free)	Ethernet interface LFAST interface Nexus Aurora -40 to +125 °C
SPC5742PFK1MLQ9	1.5 MB/192 KB	144 LQFP (Pb free)	-40 to +125 °C
SPC5742PGK1MMM9	1.5 MB/192 KB	257 MAPBGA (Pb free)	Ethernet interface LFAST interface Nexus Aurora -40 to +125 °C
SPC5741PFK1MLQ9	1 MB/128 KB	144 LQFP (Pb free)	-40 to +125 °C
SPC5741PGK1MMM9	1 MB/128 KB	257 MAPBGA (Pb free)	Ethernet interface LFAST interface Nexus Aurora -40 to +125 °C